

Search Notes

Application/Control No.

10/621,451

Examiner

Hien N. Nguyen

Applicant(s)/Patent under
Reexamination

TANAKA, YOSHIYUKI

Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	185.29	1/15/2005	HN
	185.11		
	185.09		
	185.12		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1/15/2005	HN